# N-Channel Power MOSFET 800 V, 4.5 $\Omega$

### **Features**

- ESD Diode-Protected Gate
- 100% Avalanche Tested
- 100% Rg Tested
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

# ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25°C unless otherwise noted)

Rating	Symbol	NDD	NDF	Unit
Drain-to-Source Voltage	V <sub>DSS</sub>	800		V
Continuous Drain Current R <sub>θJC</sub>	I <sub>D</sub>	2.9	3.3 (Note 1)	Α
Continuous Drain Current $R_{\theta JC}$ , $T_A = 100^{\circ}C$	I <sub>D</sub>	1.9	2.1 (Note 1)	Α
Pulsed Drain Current, V <sub>GS</sub> @ 10 V	I <sub>DM</sub>	12	13	Α
Power Dissipation $R_{\theta JC}$	$P_{D}$	96	25	W
Gate-to-Source Voltage	V <sub>GS</sub>	±30		V
Single Pulse Avalanche Energy, I <sub>D</sub> = 2.5 A	E <sub>AS</sub>	100		mJ
ESD (HBM) (JESD22-A114)	V <sub>esd</sub>	2300		V
RMS Isolation Voltage (t = 0.3 sec., R.H. ≤ 30%, T <sub>A</sub> = 25°C) (Figure 14)	V <sub>ISO</sub>		4500	V
Peak Diode Recovery (Note 2)	dv/dt	4.5		V/ns
Continuous Source Current (Body Diode)	I <sub>S</sub>	3.3		Α
Maximum Temperature for Soldering Leads	TL	260		°C
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150		°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. Limited by maximum junction temperature
- 2.  $I_S = 3.3 \text{ Å}, \text{ di/dt} \le 100 \text{ A/}\mu\text{s}, V_{DD} \le \text{BV}_{DSS}, T_J = +150 ^{\circ}\text{C}$

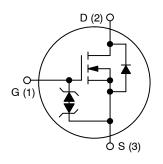


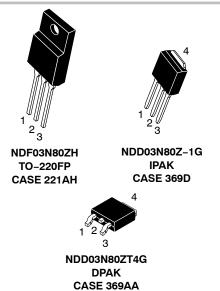
# ON Semiconductor®

# http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX
800 V	4.5 Ω @ 10 V

### **N-Channel**





## MARKING AND ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 6 of this data sheet.

# THERMAL RESISTANCE

Parameter		Symbol	Value	Unit
Junction-to-Case (Drain)	NDF03N80Z NDD03N80Z	$R_{ heta JC}$	4.0 1.3	°C/W
Junction-to-Ambient Steady State	(Note 3) NDF03N80Z (Note 4) NDD03N80Z (Note 3) NDD03N80Z-1	$R_{ hetaJA}$	50 33 96	

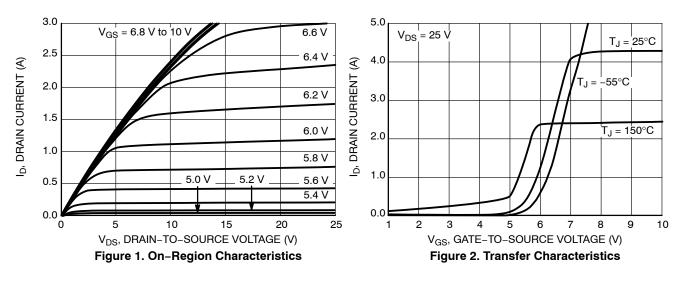
- 3. Insertion mounted
- 4. Surface mounted on FR4 board using 1" sq. pad size (Cu area = 1.127" sq [2 oz] including traces).

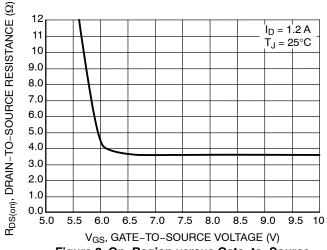
# **ELECTRICAL CHARACTERISTICS** (T<sub>1</sub> = 25°C unless otherwise noted)

Characteristic	Symbol	Test Conditions	S	Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_{D} = 1 \text{ r}$	mA	800			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>	Reference to 25°C, I <sub>D</sub>	= 1 mA		870		mV/°C
Drain-to-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> = 800 V, V <sub>GS</sub> = 0 V	T <sub>J</sub> = 25°C			1.0	μА
			T <sub>J</sub> = 125°C			50	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ±20 V	•			±10	μА
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{DS} = V_{GS}$ , $I_D = 50$	μΑ	3.0	4.1	4.5	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>	Reference to 25°C, I <sub>D</sub> :	= 50 μΑ		11		mV/°C
Static Drain-to-Source On Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 1.	2 A		3.7	4.5	Ω
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 1.	2 A		2.1		S
DYNAMIC CHARACTERISTICS							
Input Capacitance (Note 6)	C <sub>iss</sub>				440		pF
Output Capacitance (Note 6)	C <sub>oss</sub>	\/ 25 \/ \/ 0 \/ f	_ 1 M⊔-		52		1
Reverse Transfer Capacitance (Note 6)	C <sub>rss</sub>	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$			9.0		
Total Gate Charge (Note 6)	$Q_g$				17		nC
Gate-to-Source Charge (Note 6)	$Q_{gs}$				3.5		1
Gate-to-Drain ("Miller") Charge (Note 6)	Q <sub>gd</sub>	$V_{DS} = 400 \text{ V}, I_D = 3.3 \text{ A}, V$	/ <sub>GS</sub> = 10 V		9.1		
Plateau Voltage	$V_{GP}$		•		6.5		V
Gate Resistance	$R_{g}$				5.5		Ω
RESISTIVE SWITCHING CHARACTER			•		•	•	•
Turn-on Delay Time	t <sub>d(on)</sub>				9.0		ns
Rise Time	t <sub>r</sub>	V <sub>DD</sub> = 400 V. I <sub>D</sub> = 3.	3 A.		7.0		1
Turn-off Delay Time	t <sub>d(off)</sub>	$V_{DD} = 400 \text{ V}, I_D = 3.$ $V_{GS} = 10 \text{ V}, R_G = 0.$	Ω Ω		17		1
Fall Time	t <sub>f</sub>				9.0		1
SOURCE-DRAIN DIODE CHARACTER	RISTICS						
Diode Forward Voltage	$V_{SD}$		T <sub>J</sub> = 25°C		0.9	1.6	V
		$I_S = 3.0 \text{ A}, V_{GS} = 0 \text{ V}$ $T_J = 100^{\circ}\text{C}$	T <sub>J</sub> = 100°C		0.8		1
Reverse Recovery Time	t <sub>rr</sub>	$V_{GS} = 0 \text{ V}, V_{DD} = 30 \text{ V}$ $I_{S} = 3.3 \text{ A}, d_{i}/d_{t} = 100 \text{ A}/\mu\text{s}$			360		ns
Charge Time	t <sub>a</sub>				81		1
Discharge Time	t <sub>b</sub>				280		1
Reverse Recovery Charge	Q <sub>rr</sub>				1.3		μC

- 5. Pulse Width  $\leq$  380  $\mu$ s, Duty Cycle  $\leq$  2%.
- 6. Guaranteed by design.
  7. Switching characteristics are independent of operating junction temperatures.

# **TYPICAL CHARACTERISTICS**







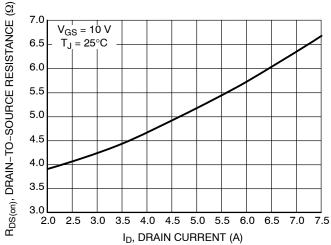


Figure 4. On-Resistance versus Drain Current and Gate Voltage

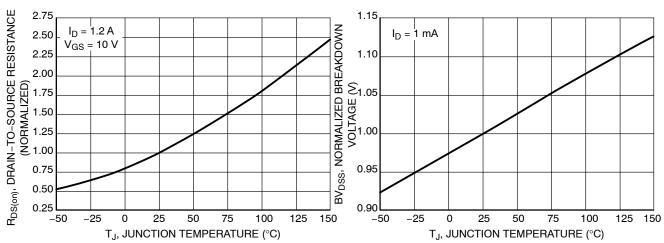


Figure 5. On–Resistance Variation with Temperature

Figure 6.  $BV_{DSS}$  Variation with Temperature

# **TYPICAL CHARACTERISTICS**

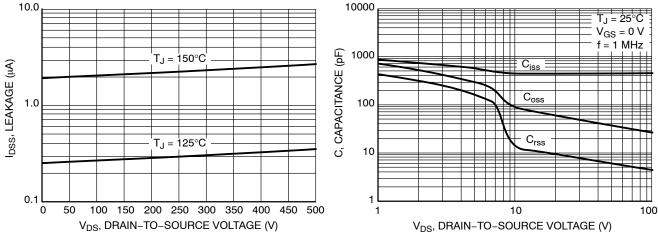


Figure 7. Drain-to-Source Leakage Current versus Voltage

Figure 8. Capacitance Variation

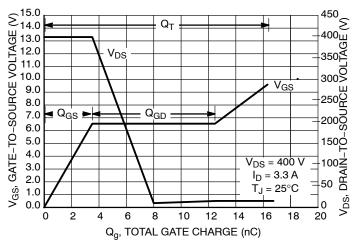


Figure 9. Gate-to-Source Voltage and Drain-to-Source Voltage versus Total Charge

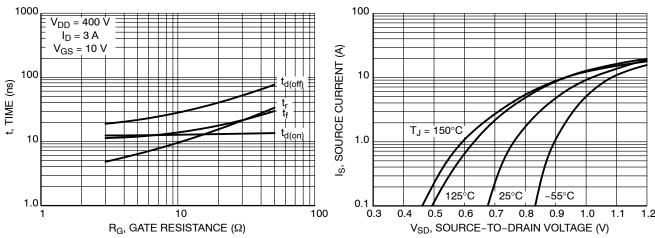


Figure 10. Resistive Switching Time Variation versus Gate Resistance

Figure 11. Diode Forward Voltage versus Current

# **TYPICAL CHARACTERISTICS**

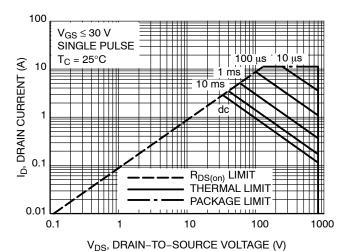


Figure 12. Maximum Rated Forward Biased
Safe Operating Area – NDD03N80Z

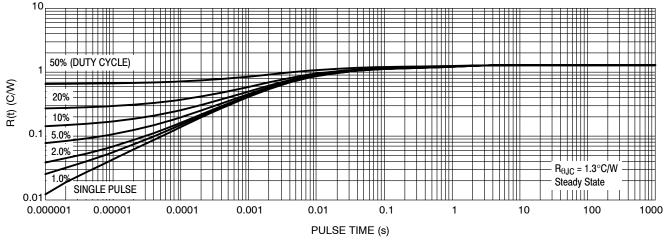


Figure 13. Thermal Impedance (Junction-to-Case) - NDD03N80Z

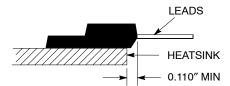


Figure 14. Isolation Test Diagram

Measurement made between leads and heatsink with all leads shorted together.

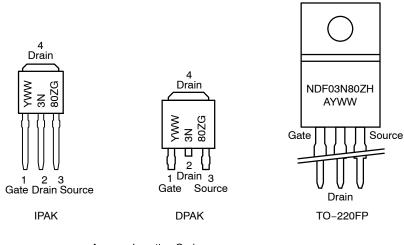
\*For additional mounting information, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

**Table 1. ORDERING INFORMATION** 

Device	Package	Shipping <sup>†</sup>
NDD03N80Z-1G	IPAK (Pb-Free, Halogen-Free)	75 Units / Rail
NDD03N80ZT4G	DPAK (Pb-Free, Halogen-Free)	2500 / Tape & Reel
NDF03N80ZH (In Development)	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

# **MARKING DIAGRAMS**



A = Location Code

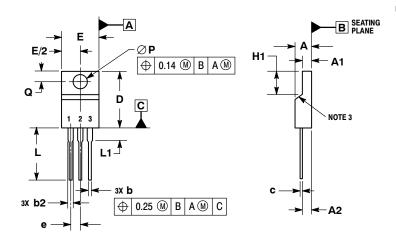
Y = Year

WW = Work Week

 $\mathsf{G},\,\mathsf{H}\quad\mathsf{=Pb\text{-}Free},\,\mathsf{Halogen\text{-}Free}\,\,\mathsf{Package}$ 

# **PACKAGE DIMENSIONS**

# TO-220 FULLPACK, 3-LEAD CASE 221AH **ISSUE C**



- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

- Y14.5M, 1994.

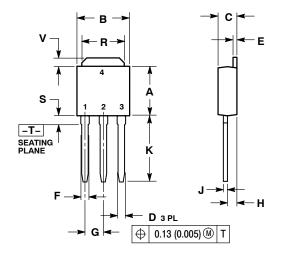
  2. CONTROLLING DIMENSION: MILLIMETERS.

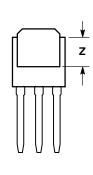
  3. CONTOU UNCONTROLLED IN THIS AREA.

  4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH AND GATE PROTRUSIONS. MOLD FLASH AND GATE PROTRUSIONS NOT IN EASH AND GATE DEPA

	MILLIMETERS			
DIM	MIN MA			
Α	4.30	4.70		
A1	2.50	2.90		
A2	2.50	2.70		
b	0.54	0.84		
b2	1.10	1.40		
С	0.49	0.79		
D	14.70	15.30		
Е	9.70	10.30		
е	2.54	BSC		
H1	6.70	7.10		
L	12.70	14.73		
L1		2.80		
Р	3.00	3.40		
œ	2.80	3.20		

# **IPAK** CASE 369D ISSUE C





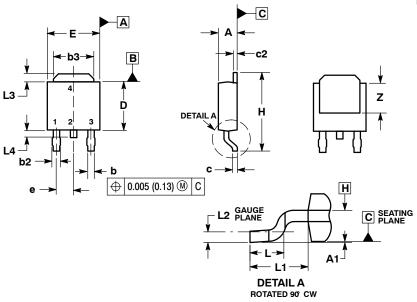
- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
   CONTROLLING DIMENSION: INCH.

	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
E	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090	BSC	2.29 BSC	
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
٧	0.035	0.050	0.89	1.27
Z	0.155		3.93	

# PACKAGE DIMENSIONS

# **DPAK (SINGLE GUAGE)**

CASE 369AA ISSUE B

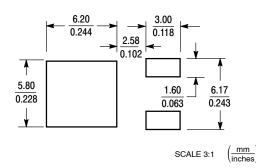


#### NOTES

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0 006 INCHES PER SIDE
- 5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INCHES		MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.030	0.045	0.76	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
Е	0.250	0.265	6.35	6.73	
е	0.090	BSC	2.29 BSC		
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.108	REF	2.74	2.74 REF	
L2	0.020 BSC		0.51	BSC	
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

# **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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